

SN54HC595, SN74HC595 8-BIT SHIFT REGISTERS WITH 3-STATE OUTPUT REGISTERS

SCLS041C – DECEMBER 1982 – REVISED JUNE 2000

- 8-Bit Serial-In, Parallel-Out Shift
- High-Current 3-State Outputs Can Drive up to 15 LSTTL Loads
- Shift Register Has Direct Clear
- Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

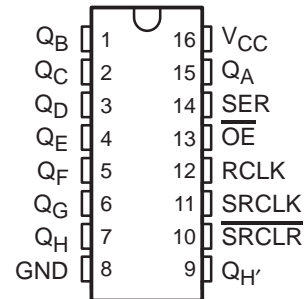
description

The 'HC595 devices contain an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. The storage register has parallel 3-state outputs. Separate clocks are provided for both the shift and storage register. The shift register has a direct overriding clear ($\overline{\text{SRCLR}}$) input, serial (SER) input, and serial outputs for cascading. When the output-enable ($\overline{\text{OE}}$) input is high, the outputs are in the high-impedance state.

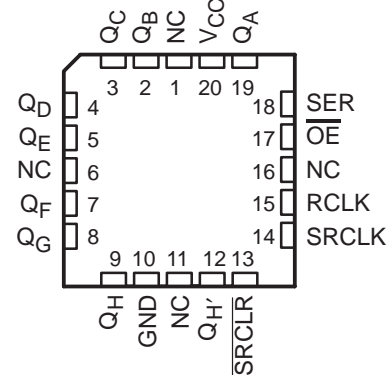
Both the shift register clock (SRCLK) and storage register clock (RCLK) are positive-edge triggered. If both clocks are connected together, the shift register always is one clock pulse ahead of the storage register.

The SN54HC595 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74HC595 is characterized for operation from -40°C to 85°C .

SN54HC595 . . . J OR W PACKAGE
SN74HC595 . . . D OR N PACKAGE
(TOP VIEW)



SN54HC595 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

 **TEXAS
INSTRUMENTS**

POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

Copyright © 2000, Texas Instruments Incorporated
On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

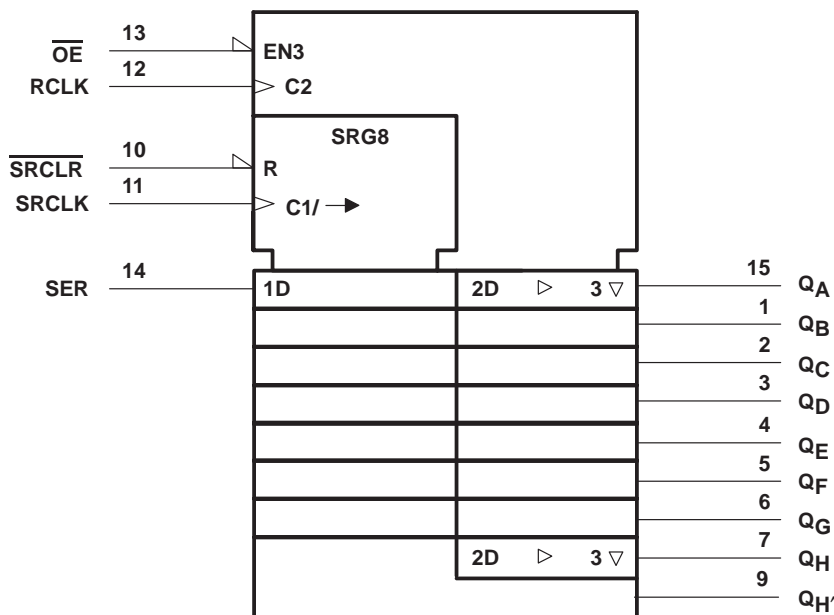
SN54HC595, SN74HC595 8-BIT SHIFT REGISTERS WITH 3-STATE OUTPUT REGISTERS

SCLS041C – DECEMBER 1982 – REVISED JUNE 2000

FUNCTION TABLE

INPUTS					FUNCTION
SER	SRCLK	SRCLR	RCLK	OE	
X	X	X	X	H	Outputs Q _A –Q _H are disabled.
X	X	X	X	L	Outputs Q _A –Q _H are enabled.
X	X	L	X	X	Shift register is cleared.
L	↑	H	X	X	First stage of the shift register goes low. Other stages store the data of previous stage, respectively.
H	↑	H	X	X	First stage of the shift register goes high. Other stages store the data of previous stage, respectively.
X	↓	H	X	X	Shift-register state is not changed.
X	X	X	↑	X	Shift-register data is stored in the storage register.
X	X	X	↓	X	Storage-register state is not changed.

logic symbol†

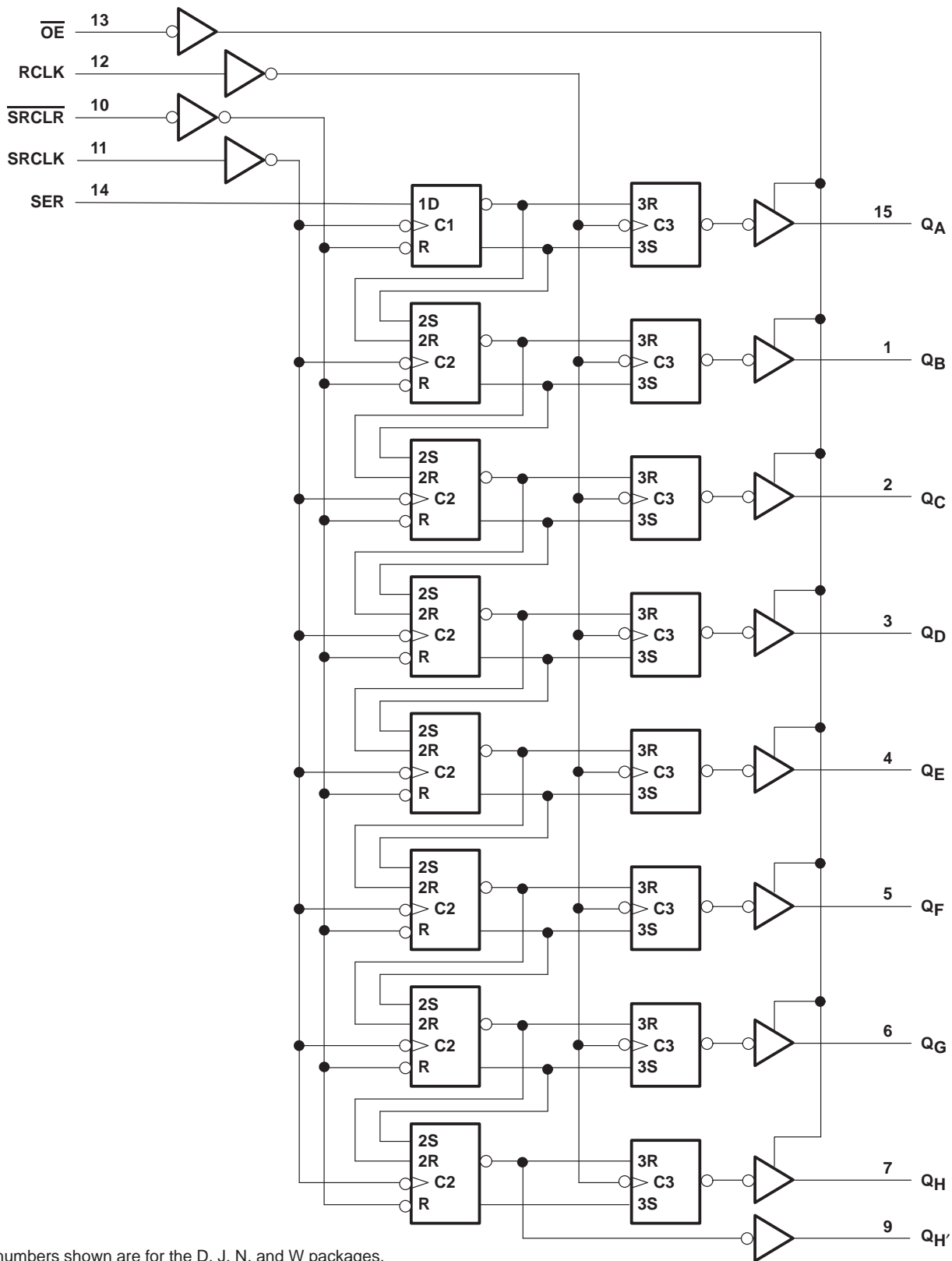


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, J, N, and W packages.

SN54HC595, SN74HC595
8-BIT SHIFT REGISTERS
WITH 3-STATE OUTPUT REGISTERS

SCLS041C – DECEMBER 1982 – REVISED JUNE 2000

logic diagram (positive logic)



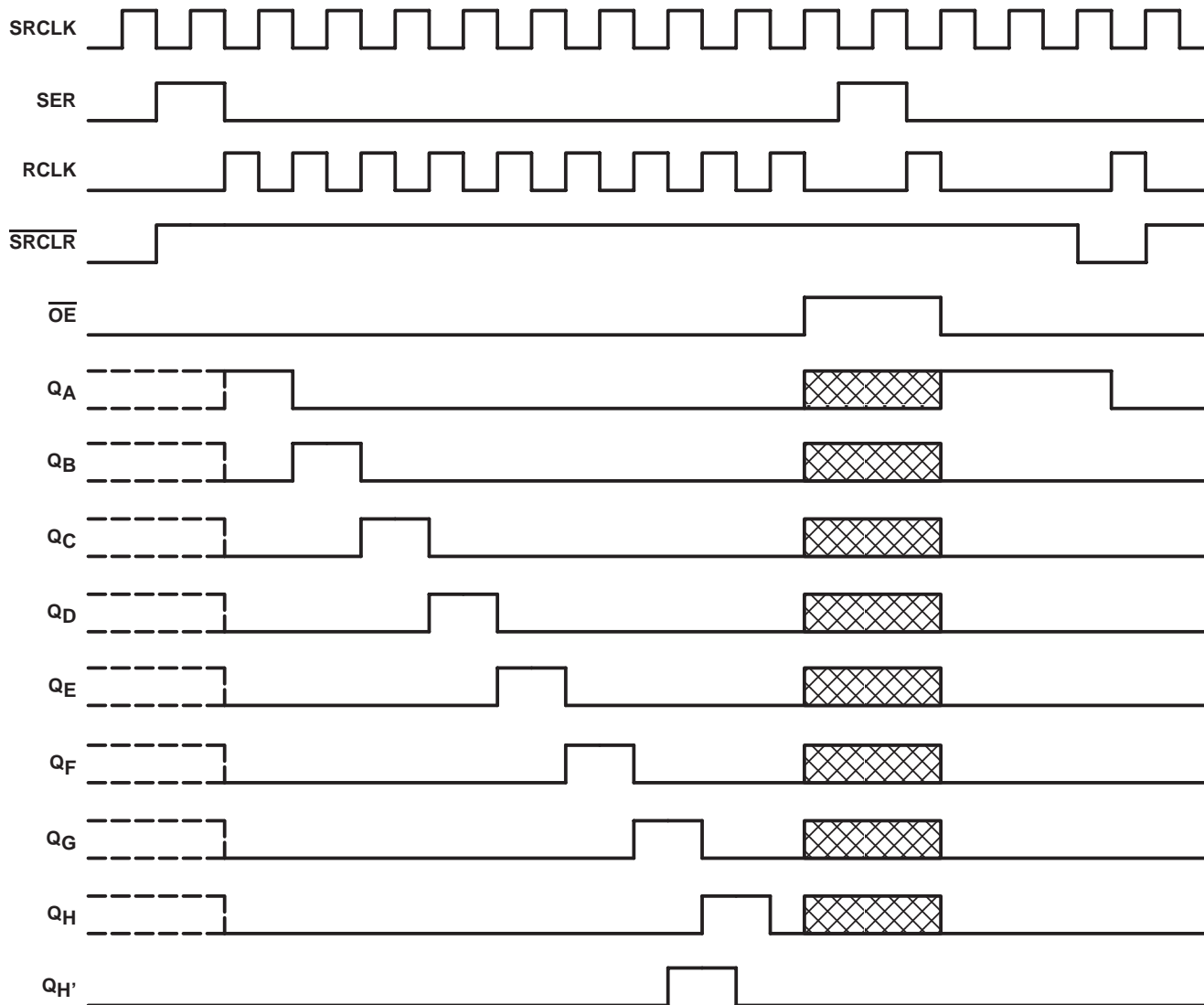
Pin numbers shown are for the D, J, N, and W packages.



SN54HC595, SN74HC595
8-BIT SHIFT REGISTERS
WITH 3-STATE OUTPUT REGISTERS

SCLS041C – DECEMBER 1982 – REVISED JUNE 2000

timing diagram



SN54HC595, SN74HC595
8-BIT SHIFT REGISTERS
WITH 3-STATE OUTPUT REGISTERS
SCLS041C – DECEMBER 1982 – REVISED JUNE 2000

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V_{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 2): D package	73°C/W
N package	67°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

		SN54HC595			SN74HC595			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	2	5	6	2	5	6	V
V_{IH}	High-level input voltage	$V_{CC} = 2$ V		1.5	$V_{CC} = 2$ V		1.5	V
		$V_{CC} = 4.5$ V		3.15	$V_{CC} = 4.5$ V		3.15	
		$V_{CC} = 6$ V		4.2	$V_{CC} = 6$ V		4.2	
V_{IL}	Low-level input voltage	$V_{CC} = 2$ V		0	0.5	$V_{CC} = 2$ V		V
		$V_{CC} = 4.5$ V		0	1.35	$V_{CC} = 4.5$ V		
		$V_{CC} = 6$ V		0	1.8	$V_{CC} = 6$ V		
V_I	Input voltage	0	V_{CC}		0	V_{CC}		V
V_O	Output voltage	0	V_{CC}		0	V_{CC}		V
t_t^\ddagger	Input transition (rise and fall) time	$V_{CC} = 2$ V		0	1000	$V_{CC} = 2$ V		ns
		$V_{CC} = 4.5$ V		0	500	$V_{CC} = 4.5$ V		
		$V_{CC} = 6$ V		0	400	$V_{CC} = 6$ V		
T_A	Operating free-air temperature	–55	125		–40	85		°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

‡ If this device is used in the threshold region (from $V_{ILmax} = 0.5$ V to $V_{IHmin} = 1.5$ V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at $t_t = 1000$ ns and $V_{CC} = 2$ V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.



SN54HC595, SN74HC595
8-BIT SHIFT REGISTERS
WITH 3-STATE OUTPUT REGISTERS

SCLS041C – DECEMBER 1982 – REVISED JUNE 2000

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V _{CC}	T _A = 25°C			SN54HC595		SN74HC595		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V _{OH}	V _I = V _{IH} or V _{IL}	I _{OH} = -20 μA	2 V	1.9	1.998		1.9		1.9	V	
			4.5 V	4.4	4.499		4.4		4.4		
			6 V	5.9	5.999		5.9		5.9		
		4.5 V	Q _H ', I _{OH} = -4 mA	3.98	4.3		3.7		3.84		
			Q _A -Q _H , I _{OH} = -6 mA	3.98	4.3		3.7		3.84		
			6 V	5.48	5.8		5.2		5.34		
			Q _A -Q _H , I _{OH} = -7.8 mA	5.48	5.8		5.2		5.34		
V _{OL}	V _I = V _{IH} or V _{IL}	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		V	
			4.5 V		0.001	0.1		0.1			
			6 V		0.001	0.1		0.1			
		4.5 V	Q _H ', I _{OL} = 4 mA		0.17	0.26		0.4			0.33
			Q _A -Q _H , I _{OL} = 6 mA		0.17	0.26		0.4			0.33
		6 V	Q _H ', I _{OL} = 5.2 mA		0.15	0.26		0.4			0.33
			Q _A -Q _H , I _{OL} = 7.8 mA		0.15	0.26		0.4			0.33
I _I	V _I = V _{CC} or 0	6 V		±0.1	±100		±1000		±1000	nA	
I _{OZ}	V _O = V _{CC} or 0	6 V		±0.01	±0.5		±10		±5	μA	
I _{CC}	V _I = V _{CC} or 0, I _O = 0	6 V			8		160		80	μA	
C _i		2 V to 6 V			3	10		10		10	pF



SN54HC595, SN74HC595
8-BIT SHIFT REGISTERS
WITH 3-STATE OUTPUT REGISTERS
 SCLS041C – DECEMBER 1982 – REVISED JUNE 2000

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		V _{CC}	T _A = 25°C		SN54HC595		SN74HC595		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	2 V	0	6	0	4.2	0	5	MHz
		4.5 V	0	31	0	21	0	25	
		6 V	0	36	0	25	0	29	
t _w	SRCLK or RCLK high or low	2 V	80		120		100		ns
		4.5 V	16		24		20		
		6 V	14		20		17		
	$\overline{\text{SRCLR}}$ low	2 V	80		120		100		
		4.5 V	16		24		20		
		6 V	14		20		17		
t _{su}	SER before SRCLK↑	2 V	100		150		125		ns
		4.5 V	20		30		25		
		6 V	17		25		21		
	SRCLK↑ before RCLK↑†	2 V	75		113		94		
		4.5 V	15		23		19		
		6 V	13		19		16		
	$\overline{\text{SRCLR}}$ low before RCLK↑	2 V	50		75		65		
		4.5 V	10		15		13		
		6 V	9		13		11		
	$\overline{\text{SRCLR}}$ high (inactive) before SRCLK↑	2 V	50		75		60		
		4.5 V	10		15		12		
		6 V	9		13		11		
t _h	Hold time, SER after SRCLK↑	2 V	0		0		0		ns
		4.5 V	0		0		0		
		6 V	0		0		0		

† This setup time allows the storage register to receive stable data from the shift register. The clocks can be tied together, in which case the shift register is one clock pulse ahead the storage register.

SN54HC595, SN74HC595
8-BIT SHIFT REGISTERS
WITH 3-STATE OUTPUT REGISTERS

SCLS041C – DECEMBER 1982 – REVISED JUNE 2000

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	T _A = 25°C			SN54HC595		SN74HC595		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f _{max}			2 V	6	26		4.2		5	MHz	
			4.5 V	31	38		21		25		
			6 V	36	42		25		29		
t _{pd}	SRCLK	Q _{H'}	2 V		50	160		240		200	ns
			4.5 V		17	32		48		40	
			6 V		14	27		41		34	
	RCLK	Q _A -Q _H	2 V		50	150		225		187	
			4.5 V		17	30		45		37	
			6 V		14	26		38		32	
t _{PHL}	$\overline{\text{SRCLR}}$	Q _{H'}	2 V		51	175		261		219	ns
			4.5 V		18	35		52		44	
			6 V		15	30		44		37	
t _{en}	$\overline{\text{OE}}$	Q _A -Q _H	2 V		40	150		225		187	ns
			4.5 V		15	30		45		37	
			6 V		13	26		38		32	
t _{dis}	$\overline{\text{OE}}$	Q _A -Q _H	2 V		42	200		300		250	ns
			4.5 V		23	40		60		50	
			6 V		20	34		51		43	
t _t		Q _A -Q _H	2 V		28	60		90		75	ns
			4.5 V		8	12		18		15	
			6 V		6	10		15		13	
		Q _{H'}	2 V		28	75		110		95	
			4.5 V		8	15		22		19	
			6 V		6	13		19		16	

switching characteristics over recommended operating free-air temperature range, $C_L = 150 \text{ pF}$ (unless otherwise noted) (see Figure 1)

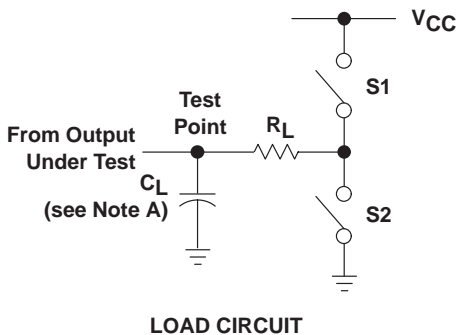
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	T _A = 25°C			SN54HC595		SN74HC595		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t _{pd}	RCLK	Q _A -Q _H	2 V		60	200		300		250	ns
			4.5 V		22	40		60		50	
			6 V		19	34		51		43	
t _{en}	$\overline{\text{OE}}$	Q _A -Q _H	2 V		70	200		298		250	ns
			4.5 V		23	40		60		50	
			6 V		19	34		51		43	
t _t		Q _A -Q _H	2 V		45	210		315		265	ns
			4.5 V		17	42		63		53	
			6 V		13	36		53		45	

operating characteristics, T_A = 25°C

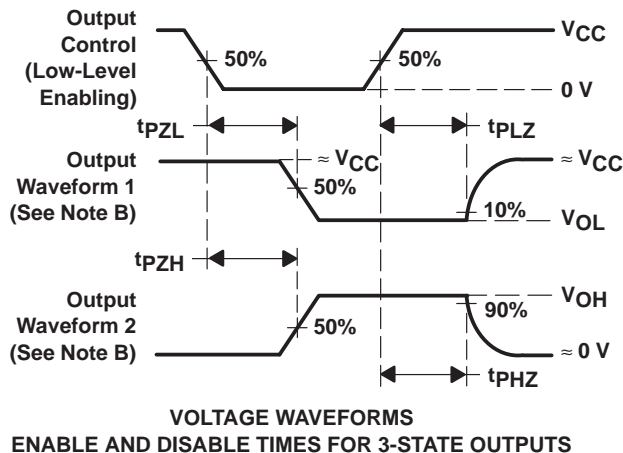
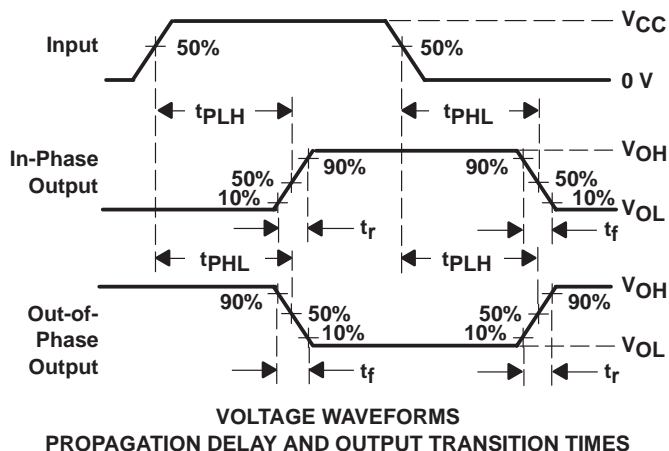
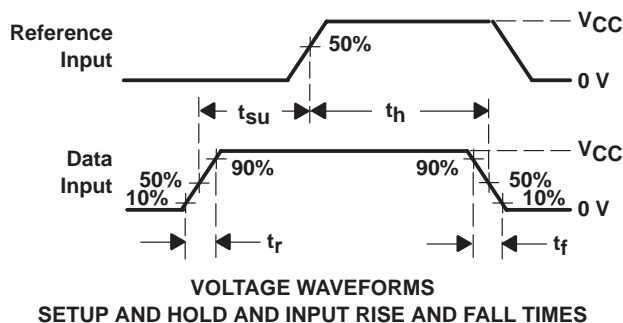
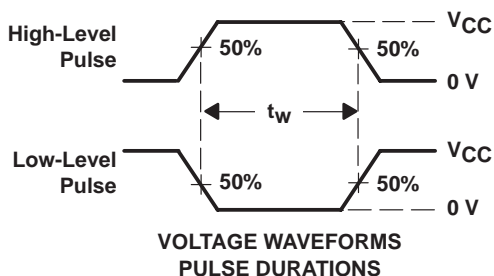
PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	No load	400	pF



PARAMETER MEASUREMENT INFORMATION



PARAMETER	R_L	C_L	S1	S2
t_{en}	1 k Ω	50 pF or 150 pF	Open	Closed
			Closed	Open
t_{dis}	1 k Ω	50 pF	Open	Closed
			Closed	Open
t_{pd} or t_t	—	50 pF or 150 pF	Open	Open



- NOTES: A. C_L includes probe and test-fixture capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1$ MHz, $Z_O = 50 \Omega$, $t_r = 6$ ns, $t_f = 6$ ns.
D. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
E. The outputs are measured one at a time with one input transition per measurement.
F. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
G. t_{PZL} and t_{PZH} are the same as t_{en} .
H. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgment, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Customers are responsible for their applications using TI components.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.